## Notice of References Cited Application/Control No. 09/057,838 Applicant(s)/Patent Under Reexamination VAN DE VEN ET AL. Examiner XIAO M. WU Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,115,286	05-1992	Camras et al.	257/94
	В	US-5,661,074	08-1997	Tischler, Michael A.	438/32
	С	US-5,812,105	09-1998	Van de Ven, Antony Paul	345/83
	D	US-			
	Е	US-	]		
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			-
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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	V							
	w							
	х							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.